



Unidirectional high power transient voltage suppressor in QFN-2L



QFN-2L 1.6 X 1.0 X 0.55 mm



Pin configuration

Product label ONGEVITA TO A COMMITMEN

Product status link

ESDA7P60-1U1M, ESDA7P120-1U1M, ESDA8P80-1U1M, ESDA13P70-1U1M, ESDA15P60-1U1M, ESDA17P50-1U1M, ESDA20P50-1U1M, ESDA25P35-1U1M.

Product summary						
Order code	See Table 13.					
Package	QFN-2L 1.6 x 1.0					
Packing	Tape and reel					

Features

- Single line unidirectional EOS and ESD protection diode
- Protects one I/O line or power line
- Stand-off voltage range from 5.5 V to 22 V
- Low leakage current at V_{RM}
- High peak pulse power (8/20 μs) up to 1400 W
- Low power derating across the temperature range
- Fast turn-on and low clamping voltage
- Operating Tj max: 150 °C
- 1.6 mm x 1.0 mm QFN package saves board space
 - 75 % smaller in footprint compared to SOD-123FL
- ECOPACK2 ROHS compliant component
- Complies with J-STD-020 MSL level 1
- Complies with IEC 61000-4-5 (Lightning)
 - 8/20 μs: up to 120 A
- Complies with IEC 61000-4-2 level 4
 - ±30 kV (air discharge)
 - ±30 kV (contact discharge)

Applications

Where transient overvoltage protection in ESD sensitive equipment is required, such as:

- USB type-C Vbus
- USB-PD up to 20 V
- · Battery protection (Vbatt) / charger port
- Power supply line protection
- Hard disks and SSD
- Portable multimedia devices and accessories
- Industrial application
- Medical and healthcare equipment

Description

ESDAxxPxxx-1U1M transient voltage suppressor (TVS) series are designed for use in harsh environments to protect sensitive electronics from damage or latch-up due to electrical overstress (EOS), lightning surge and ESD without aging effect and performance drifts.

The series features desirable characteristics for board level protection including fast response time, excellent clamping voltage capability compared to standard TVS devices, and high surge current capability with low derating across the temperature range. In addition, this series is available in a small 1.6 mm × 1.0 mm footprint, ideal for space constrained applications.

The ESDAxxPxxx-1U1M series can be evaluated thanks to the STEVAL-OET005 evaluation board.



1 Characteristics

Table 1. Absolute maximum ratings (T_{amb} = 25 °C)

Symbol	F	Parameter	Value	Unit
		IEC 61000-4-2 – C = 150 pF, R = 330 Ω:		
V_{PP}	Peak pulse voltage	Contact discharge	±30	kV
		Air discharge	±30	
P _{PP}	Peak pulse power	IEC 61000-4-5 (2Ω) – tp = $8/20 \mu s$	700 – 1400	W
I _{PP}	Peak pulse current	IEC 61000-4-5 (2Ω) – tp = 8/20 μs	See Table 2.	Α
T _{stg}	Storage junction temperature range		-55 to + 150	
Tj	Maximum operating junction temperate	Maximum operating junction temperature		
TL	Maximum lead temperature for soldering	260		

Figure 1. Electrical characteristics (definitions)

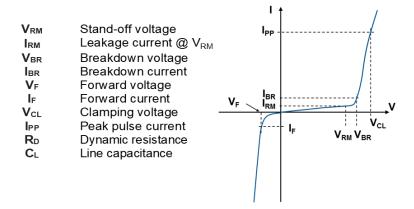


Table 2. Electrical characteristics - parameter values (T_{amb} = 25 °C, unless otherwise specified)

	V _{RM}	J	V :	at I	8	/ 20µs ⁽¹⁾	(2)	CL	V _F a	+ I_
Order code	V RM	I _{RM}	V _{BR} at I _R		V _{CL} (3)	Ірр	R _D	OL	V F G	t if
Older code	Max.	Min.	Тур.		Max.		Max.	Тур.	Тур.	
	V	μΑ	V	mA	V	Α	mΩ	pF	V	mA
ESDA7P60-1U1M	5.0	0.2	6.7	1	11.6	60	0.06	450	0.75	10
ESDA7P120-1U1M	5.5	1.5	6.8	1	11.5	120	0.035	800	0.75	10
ESDA8P80-1U1M	6.3	1.0	7.3	1	13.2	80	0.06	480	0.75	10
ESDA13P70-1U1M	12.0	0.2	13.0	1	20.0	70	0.09	390	0.75	10
ESDA15P60-1U1M	13.2	0.05	14.3	1	22.7	57	0.10	335	0.75	10
ESDA17P50-1U1M	15.0	0.05	16.4	1	26.5	46	0.15	290	0.75	10
ESDA20P50-1U1M	18.0	0.05	19.5	1	31.0	40	0.20	240	0.75	10
ESDA25P35-1U1M	22.0	0.2	24.6	1	41.0	35	0.45	195	0.75	10

- 1. Specified by design not tested in production.
- 2. Measured from pin 1 to 2, in accordance with IEC 61000-4-5 (8/20 µs current waveform).
- 3. To calculate typical clamping voltage at other surge level, use the following formula: $V_{CL\ typ} = V_{BR\ typ.} + R_D\ x\ I_{PPappli}$ where $I_{PPappli}$ is the surge current in the application.

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Table 3. ESDA7P60-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V_{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			5.0	V
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 5.0 V			200	nA
V_{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	6.4	6.4 6.8		V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10mA		0.75		V
V (1)	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		8.9		V
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 60 A		10.2	11.6	V
R _d (1)	Dynamic resistance	8/20 μs waveform		0.06		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		450		pF

^{1.} Specified by design – Not tested in production.

Table 4. ESDA7P120-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V_{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			5.5	V
I _R ⁽¹⁾	Reverse leakage current at V _R	Pin 1 to pin 2, V _{RM} = 5.0 V			350	nA
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 5.5 V				μA
V_{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	6.4	6.8	7.2	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10 mA		0.75		V
	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		7.7		V
V (1)		IEC 61000-4-5 surge (8/20μs), I _{PP} = 80 A		9.5	10.0	
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 100 A		10.2	10.7	V
		IEC 61000-4-5 surge (8/20μs), I _{PP} = 120 A		11.0	11.5	
R _d (1)	Dynamic resistance	8/20 µs waveform		0.035		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		800		pF

^{1.} Specified by design – Not tested in production.

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Table 5. ESDA8P80-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V_{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			6.3	V
I _R ⁽¹⁾	Reverse leakage current at V _R	Pin 1 to pin 2, V _{RM} = 5.5 V			200	nA
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 6.3 V			1.0	μA
V_{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	6.9 7.3		8.0	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10mA		0.75		V
	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		7.3		٧
V _{CL} ⁽¹⁾	FOS elemning veltage	IEC 61000-4-5 surge (8/20µs), I _{PP} = 60 A		10.8	12.0	V
	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 80 A		11.8	13.2	V
R _d ⁽¹⁾	Dynamic resistance	8/20 µs waveform		0.06		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		480		pF

^{1.} Specified by design – Not tested in production.

Table 6. ESDA13P70-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V_{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			12.0	V
I _R ⁽¹⁾	Reverse leakage current at V _R	Pin 1 to pin 2, V _{RM} = 9.0 V			100	nA
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 12.0 V			200	nA
V _{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	12.5	13.0	13.5	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10mA		0.75		V
	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		13.7		V
V _{CL} ⁽¹⁾	EOS elemning voltage	IEC 61000-4-5 surge (8/20µs), I _{PP} = 10 A		14.2	16.0	V
	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 60 A		18.4	20.0	V
R _d (1)	Dynamic resistance	8/20 µs waveform		0.09		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		390		pF

^{1.} Specified by design – Not tested in production.

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Table 7. ESDA15P60-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V _{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			13.2	V
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 13.2 V		1.0	50	nA
V _{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	13.6	14.3	15.3	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10 mA		0.75		V
(1)	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		15.2		V
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 57 A		20.8	22.7	V
R _d (1)	Dynamic resistance	8/20 μs waveform		0.1		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		335		pF

^{1.} Specified by design – Not tested in production.

Table 8. ESDA17P50-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition		Тур.	Max.	Unit
V _{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			15.0	V
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 15.0 V		1.0	50	nA
V _{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	15.6	16.4	17.4	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10 mA		0.75		V
V (1)	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		17.9		V
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 46 A		24.4	26.5	V
R _d (1)	Dynamic resistance	8/20 μs waveform		0.15		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		290		pF

^{1.} Specified by design – Not tested in production.

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Table 9. ESDA20P50-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition	Min.	Тур.	Max.	Unit
V_{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			18.0	V
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 18.0 V		1.0	50	nA
V _{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA	18.5	19.5	20.5	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10 mA		0.75		V
(1)	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		20.2		V
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 40 A		27.5	31.0	V
R _d (1)	Dynamic resistance	8/20 µs waveform		0.2		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		240		pF

^{1.} Specified by design – Not tested in production.

Table 10. ESDA25P35-1U1M Electrical characteristics (T_{amb} = 25 °C, unless otherwise specified)

Symbol	Parameter definition	Test condition		Тур.	Max.	Unit
V _{RM}	Reverse Stand-Off voltage	Pin 1 to pin 2			22.0	V
I _{RM}	Reverse leakage current at V _{RM}	Pin 1 to pin 2, V _{RM} = 22.0 V			200	nA
V _{BR}	Reverse breakdown voltage	Pin 1 to pin 2, I _{BR} = 1 mA 23		24.6	25.8	V
V _F	Forward voltage	Pin 2 to pin 1, I _F = 10 mA		0.75		V
V (1)	ESD clamping voltage	IEC 61000-4-2, C = 150 pF, R = 330 Ω , +8 kV contact discharge, measured at 30 ns		29.0	31.0	V
V _{CL} ⁽¹⁾	EOS clamping voltage	IEC 61000-4-5 surge (8/20μs), I _{PP} = 35 A		39.0	41.0	V
R _d (1)	Dynamic resistance	8/20 μs waveform		0.45		Ω
C _{I/O-GND} (1)	Line capacitance	Pin 1 to pin 2, V _{I/O} = 0 V, 1 MHz, V _{OSC} = 30 mV		195		pF

^{1.} Specified by design – Not tested in production.

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1.1 Characteristics (curves)

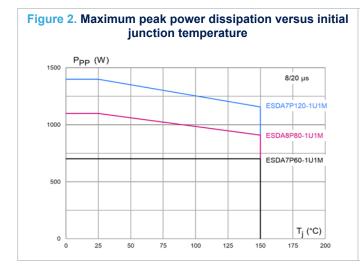


Figure 3. Maximum peak power dissipation versus initial junction temperature

Ppp (W)

Size | Size |

Figure 4. Maximum peak pulse power versus exponential pulse duration

Ppp (W)

T, initial = 25 °C

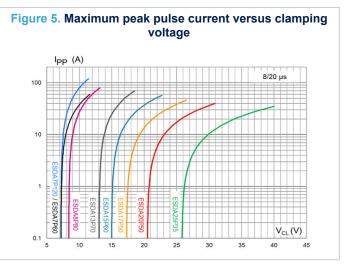
T, initial = 25 °C

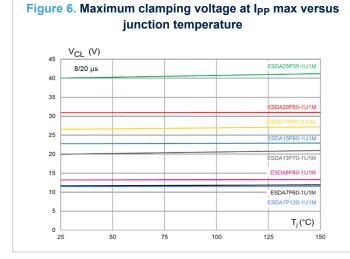
ESDA7P120 : ESDA25P35

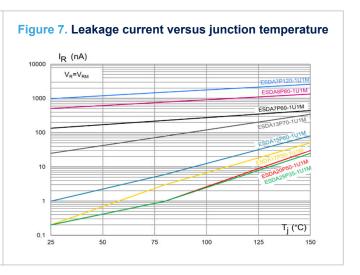
ESDA15P60 : ESDA17P50 : ESDA20P50

T, initial = 25 °C

T, initia







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Figure 8. ESDA7P120-1U1M ESD response to IEC 61000-4-2 (+8kV contact discharge)

5 V/div

25.4 Ve Ver ESD peak voltage Ver Clamping voltage © 50 ns Ver Clamping voltage © 100 ns

7.7 Ve 8 Ver Clamping voltage © 100 ns

20 ns/div

Figure 9. ESDA7P120-1U1M ESD response to IEC 61000-4-2 (-8kV contact discharge)

5 V/div

-1.2 Vo -1.6 Vo -0.997 V

Figure 10. ESDA25P35-1U1M ESD response to IEC 61000-4-2 (+8kV contact discharge)

10 V/div

20 ns/div

ESD level V_{pp} V_{cL}@30ns V_{cL}@60ns V_{cL}@100ns
+8kV 45V 26V 27V 27V

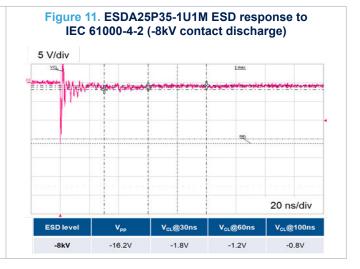
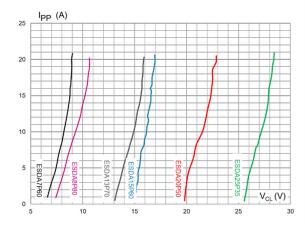


Figure 12. TLP



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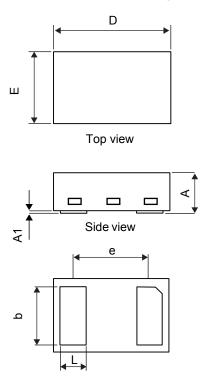


Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

2.1 QFN-2L 1.6 x 1.0 package information

Figure 13. QFN-2L 1.6 x 1.0 package outline



Bottom view

Table 11. QFN-2L 1.6 x 1.0 package mechanical data

	Dimensions							
Ref.		Millimeters		Inches ⁽¹⁾				
	Min.	Тур.	Max.	Min.	Тур.	Max.		
Α	0.51	0.55	0.60	0.0200	0.0217	0.0236		
A1	0.00	0.02	0.05	0.0000	0.0008	0.0020		
b	0.75	0.80	0.85	0.0295	0.0315	0.0335		
D	1.50	1.60	1.70	0.0590	0.0630	0.0670		
E	0.90	1.00	1.10	0.0350	0.0390	0.0440		
е		1.05			0.0413			
L	0.30	0.35	0.40	0.0118	0.01378	0.0158		

^{1.} Values in inches are converted from mm and rounded to 5 decimal digits.

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Figure 14. Recommended footprint in mm

0.70

0.55

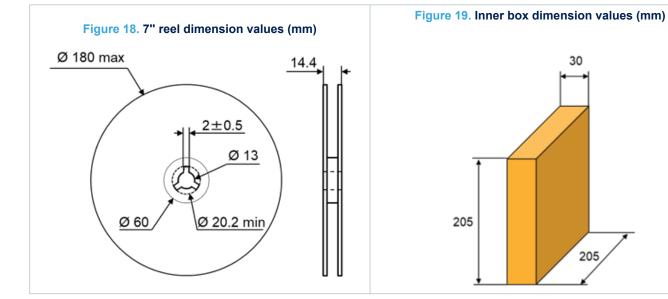
0.80

refer to Table 13. Ordering information for marking value

Pin 1 located according to EIA-481

Note: Pocket dimensions are not on scale.
Only pin 1 mark must be used to orient the component for its placement on a PCB.

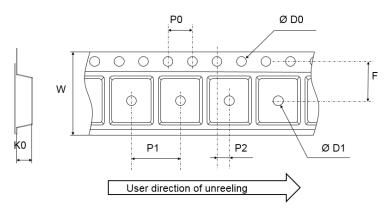




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Figure 20. Tape outline

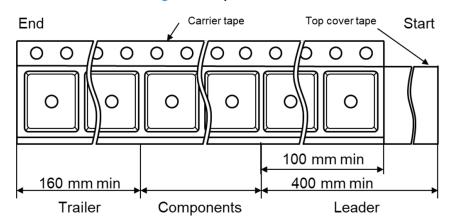


Note: Pocket dimensions are not on scale Pocket shape may vary depending on package

Table 12. Tape dimension values

	Dimensions					
Ref.	Millimeters					
	Min.	Тур.	Max.			
D0	1.50	1.55	1.60			
D1	0.50					
F	3.45	3.50	3.55			
K0	0.62	0.67	0.72			
P0	3.90	4.00	4.10			
P1	1.90	2.00	2.10			
P2	1.90	2.00	2.10			
W	7.90	8.00	8.10			

Figure 21. Tape information



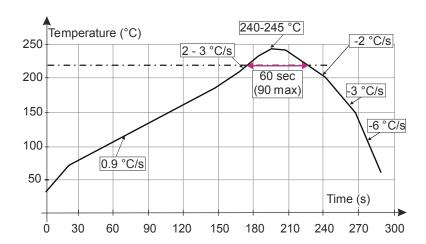
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Recommendation on PCB assembly

3.1 Reflow profile

Figure 22. ST ECOPACK recommended soldering reflow profile for PCB mounting



Note: Minimize air convection currents in the reflow oven to avoid component movement. O_2 rate inside the oven must be below 500 ppm. Maximum soldering profile corresponds to the latest IPC/JEDEC J-STD-020.

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4 Ordering information

Figure 23. Ordering information scheme

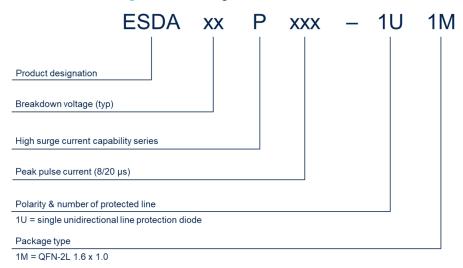


Table 13. Ordering information

Order code	Marking ⁽¹⁾	Package	Weight	Base qty.	Delivery mode
ESDA7P60-1U1M	F	QFN-2L 1.6 x 1.0	2.4 mg	8000	Tape and reel
ESDA7P120-1U1M	Е				
ESDA8P80-1U1M	J				
ESDA13P70-1U1M	G				
ESDA15P60-1U1M	J				
ESDA17P50-1U1M	L				
ESDA20P50-1U1M	R				
ESDA25P35-1U1M	Р				

^{1.} The marking can be rotated by multiples of 90° to differentiate assembly locations.

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Revision history

Table 14. Document revision history

Date	Revision	Changes
12-Sep-2023	1	Initial release.
12-Mar-2024	2	Updated Table 11.

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